

# **Measurement of charge collection in p-type microstrip sensors with SCT128 chip**

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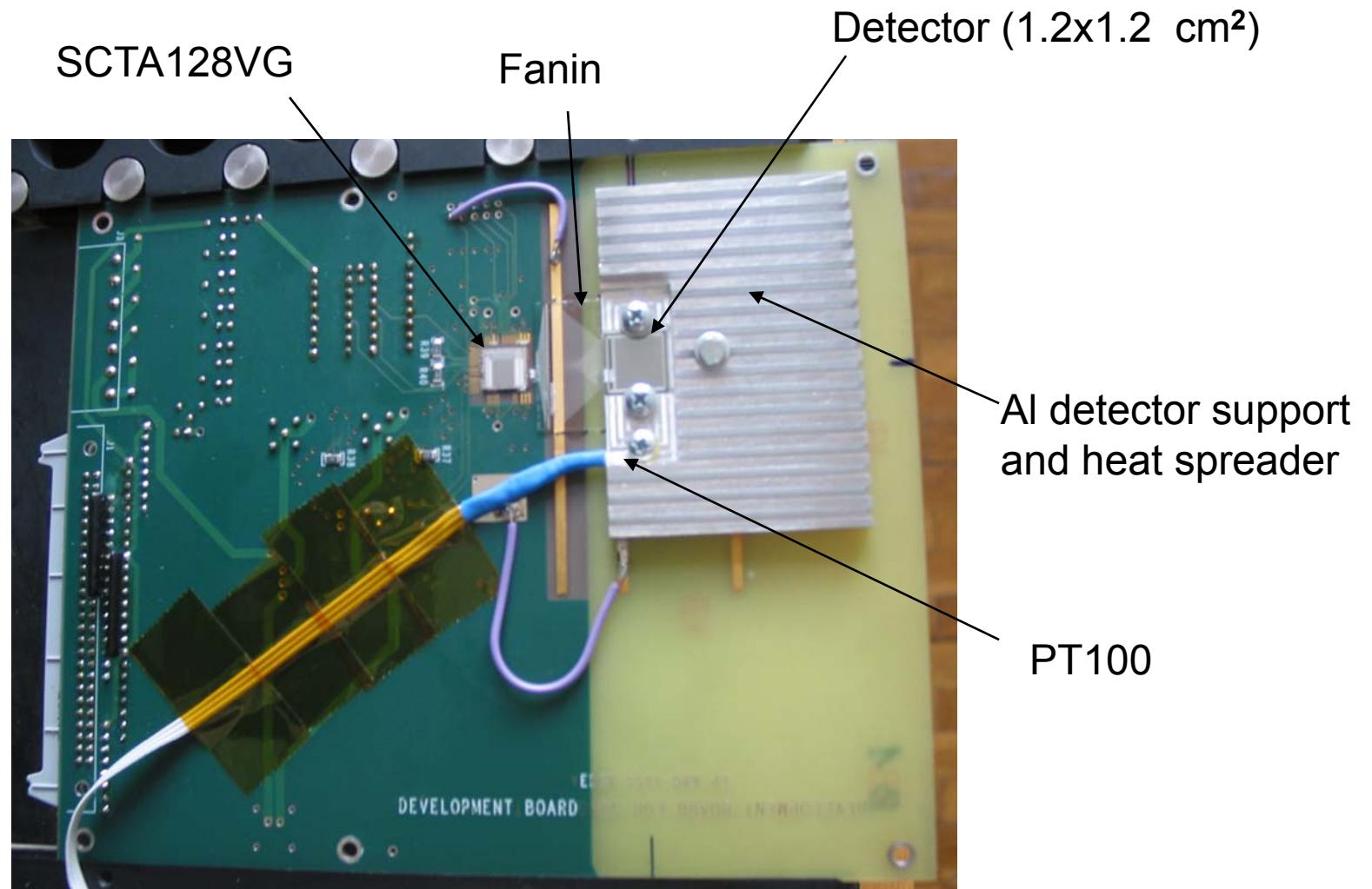


Setup for measurements with SCTA128 chip was built in Ljubljana:

- SCTA128VG chip
- drawings of test pcb from CERN (thanks to [Jan Kaplon](#))
- VME module SEQSI (for clock, commands...)
- Tektronix digital scope for data acquisition
- Cambridge LabView software for chip control (thanks to [Dave Robinson](#))
- data acquisition software (thanks to [G. Kramberger](#))
- pitch adapters from Freiburg (thanks to [Uli Parzefal](#))
- coincidence circuit made by [Erik Margan](#)
- $^{90}\text{Sr}$  source, photomultiplier, scintillator, power supplies....



## Test PCB



## Aluminium support structure

- dimensions: ~ 25 cm x 20 cm x 6 cm

$^{90}\text{Sr}$  source is inserted into the upper collimator

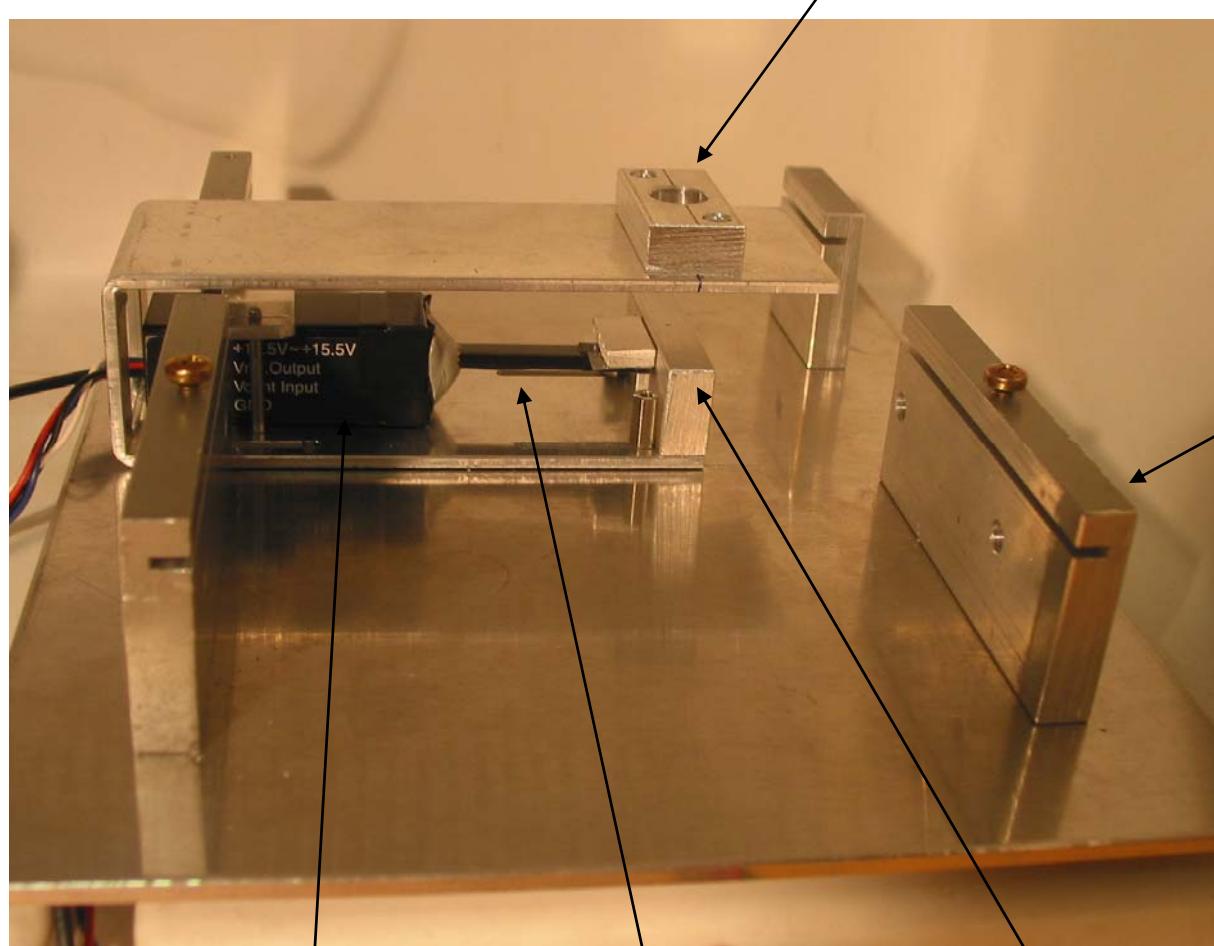


Photo Multiplier

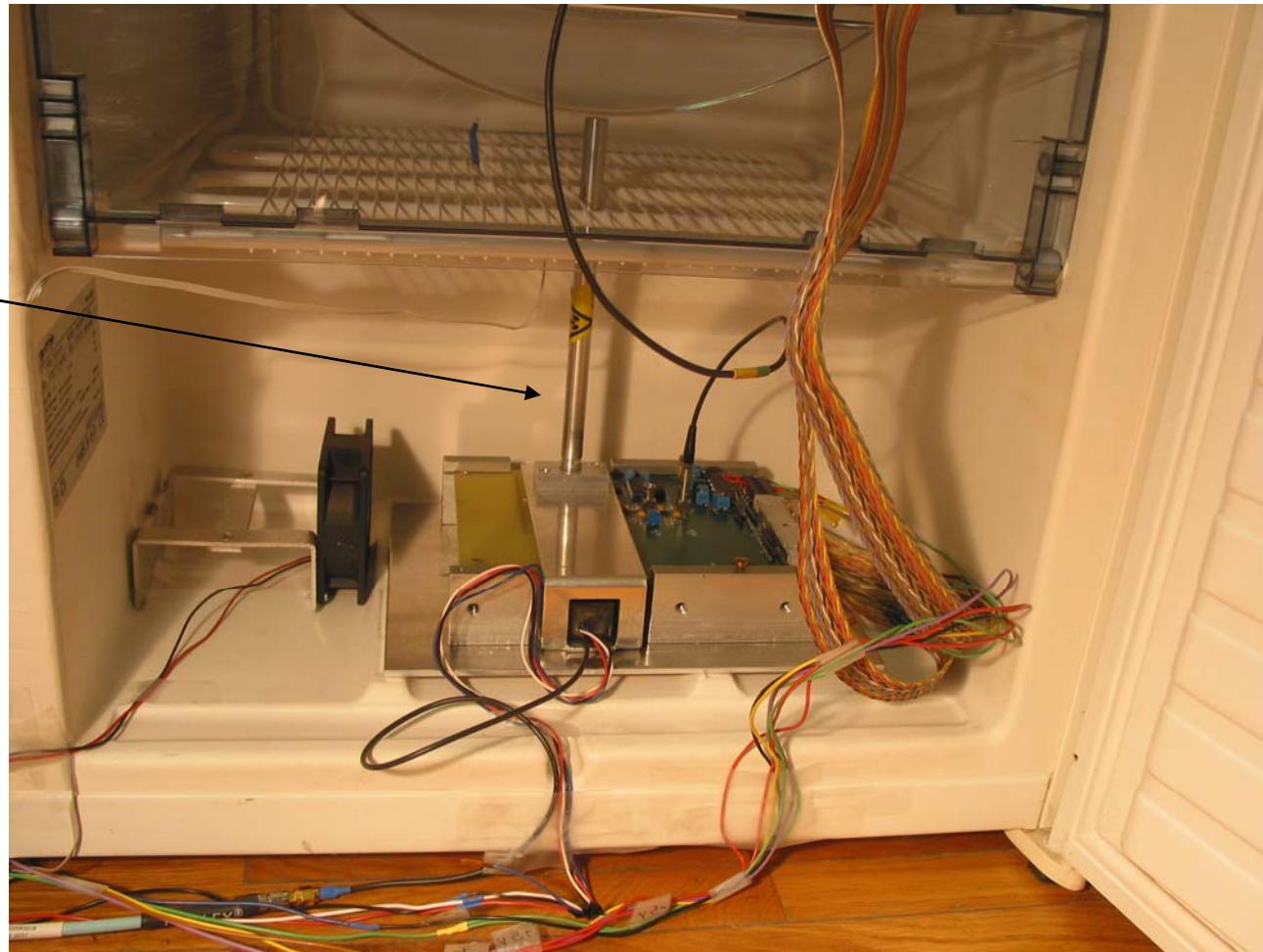
Light guide

Scintillator is under the  
lower collimator



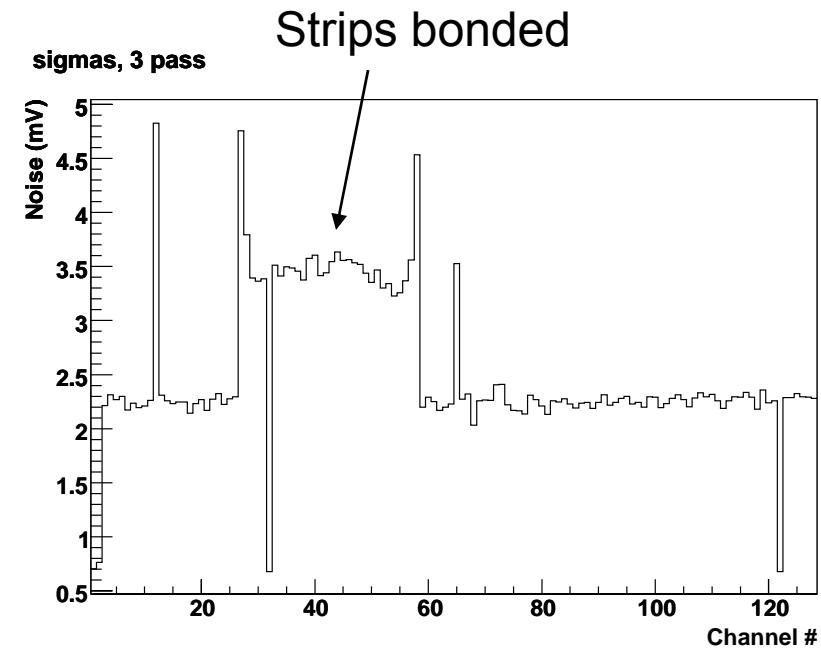
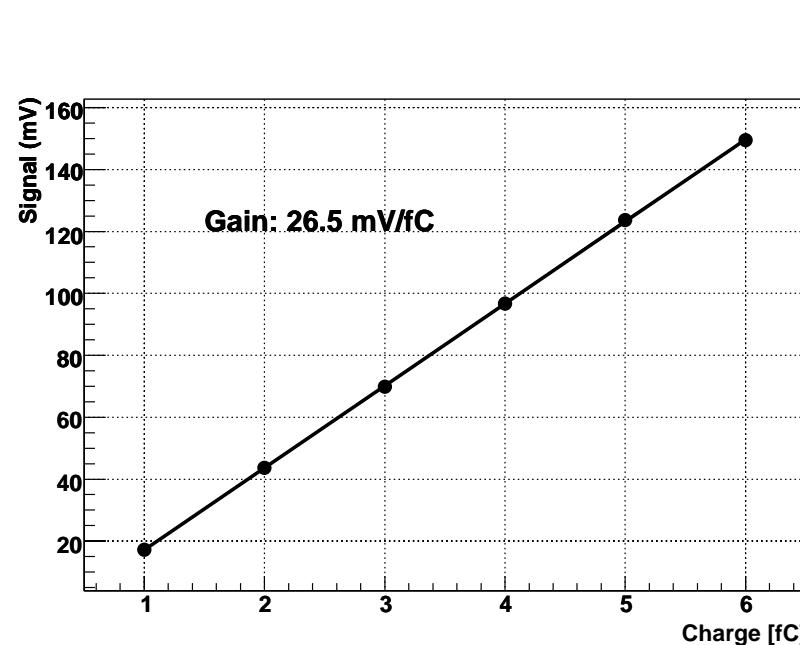
Setup in the fridge, temperature about - 20° C

$^{90}\text{Sr}$  source  
holder



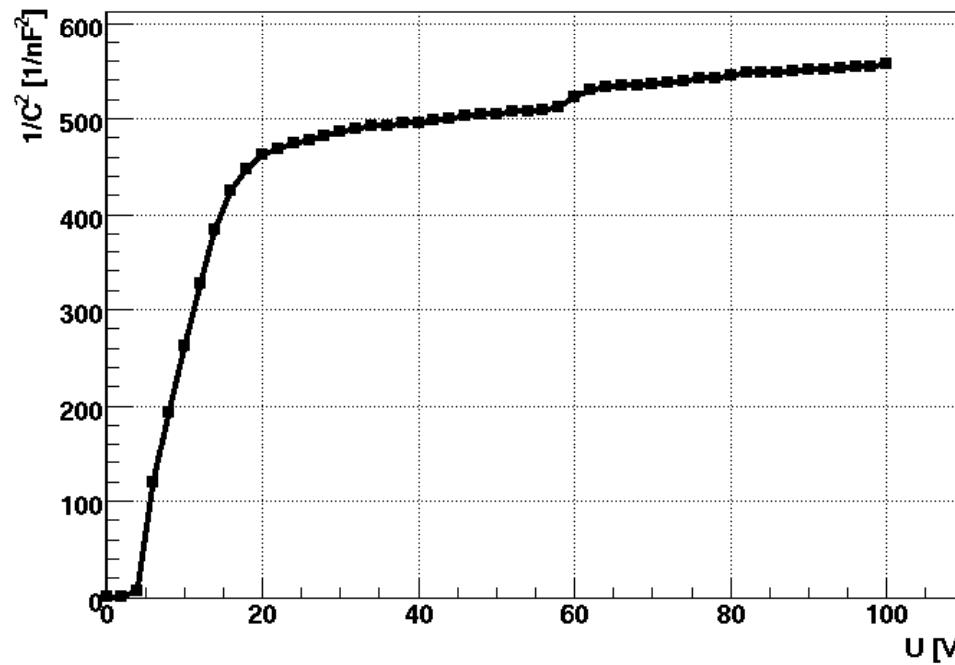
## SCTA128VG chip

- 128 channels
- charge sensitive front-end amplifier with about 20 ns peaking time
- sampled every 25 ns (40 MHz sampling clock)
- Gain =  $26.5 \text{ mV/fC} = 4.2 \mu\text{V/el}$  measured with calibration signals from on-chip capacitors ( $\sim 10\%$  accuracy)
- noise with detector connected  $\sim 800 \text{ el}$



## Detectors

- p-type, FZ material, 300  $\mu\text{m}$  thick strip detectors
- strip pitch 80  $\mu\text{m}$
- n-in-p capacitively coupled
- polysilicon biased, p-sprayed
- designed by Liverpool, produced by [Micron Semiconductor](#), sent to us by [Gianluigi Casse](#)



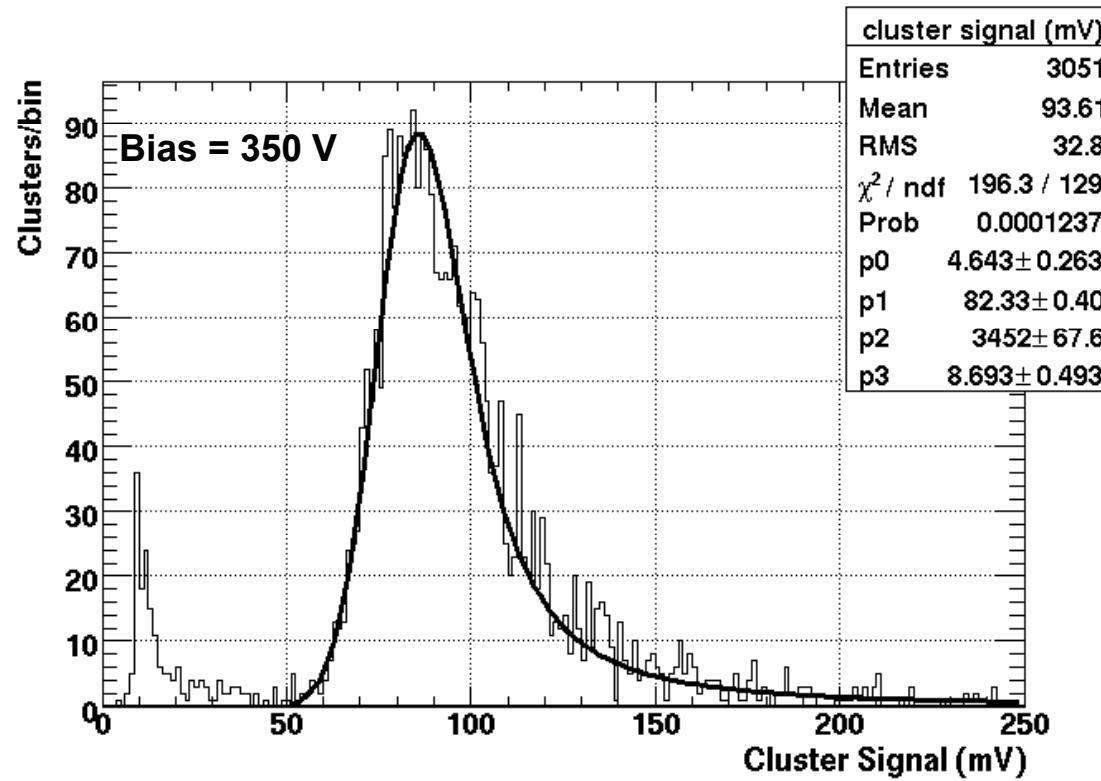
## Irradiations

- detectors were irradiated with neutrons in the TRIGA reactor in Ljubljana
- 1 MeV equivalent fluences (same fluence steps as for Liverpool):
  - $5 \cdot 10^{14} \text{ n/cm}^2$
  - $1.6 \cdot 10^{15} \text{ n/cm}^2$
  - $3 \cdot 10^{15} \text{ n/cm}^2$
- after irradiation detectors were annealed for 80 minutes at 60° C



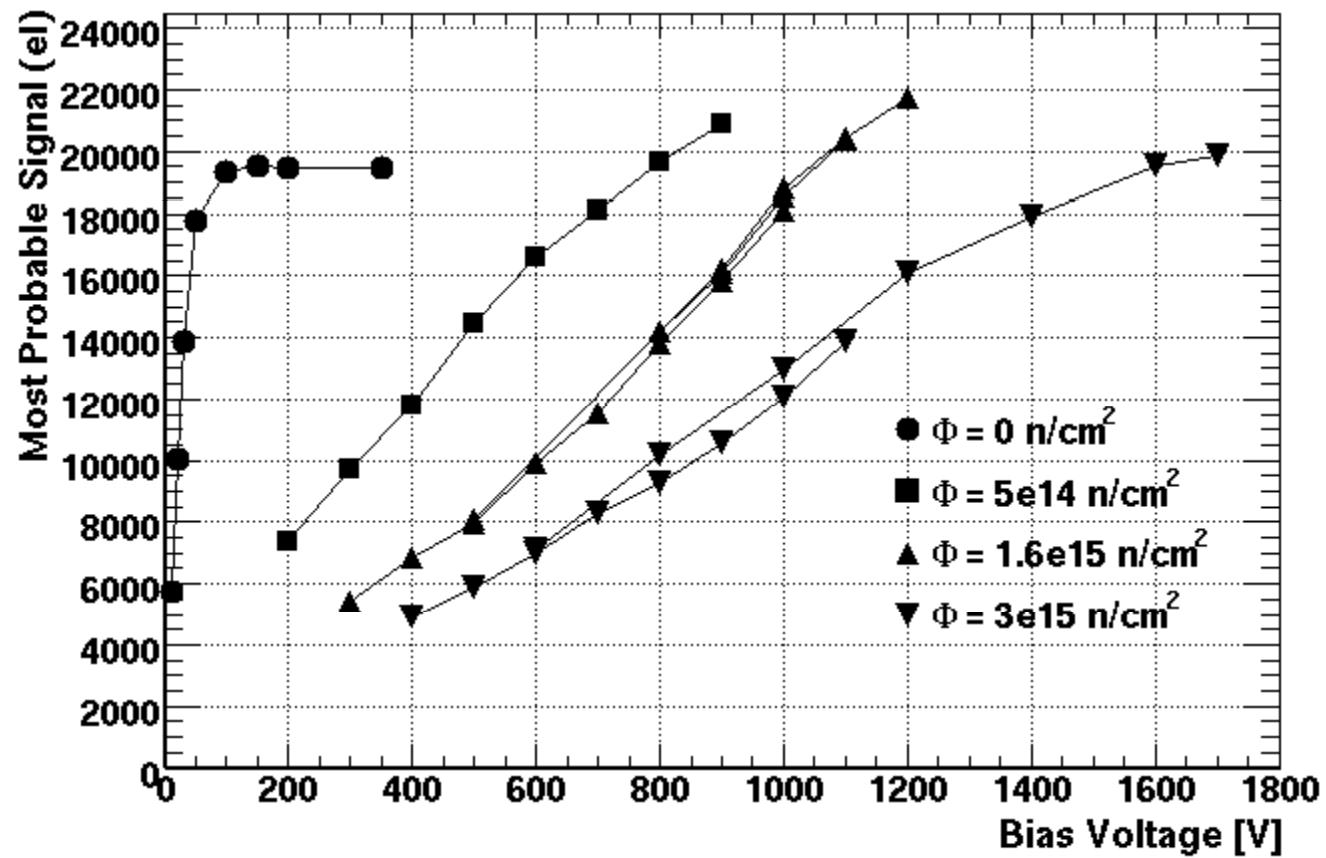
## Measurements

- trigger: signals caused by electrons from  $^{90}\text{Sr}$  source in scintillator in coincidence with 40 MHz clock edge
- spectrum of signals from strips (pedestals and common mode variations subtracted) fitted with convolution of Landau and Gauss functions  
→ “Most Probable Value” of the Landau function (parameter p1 in the plot below) returned by the fit is the measure of collected charge



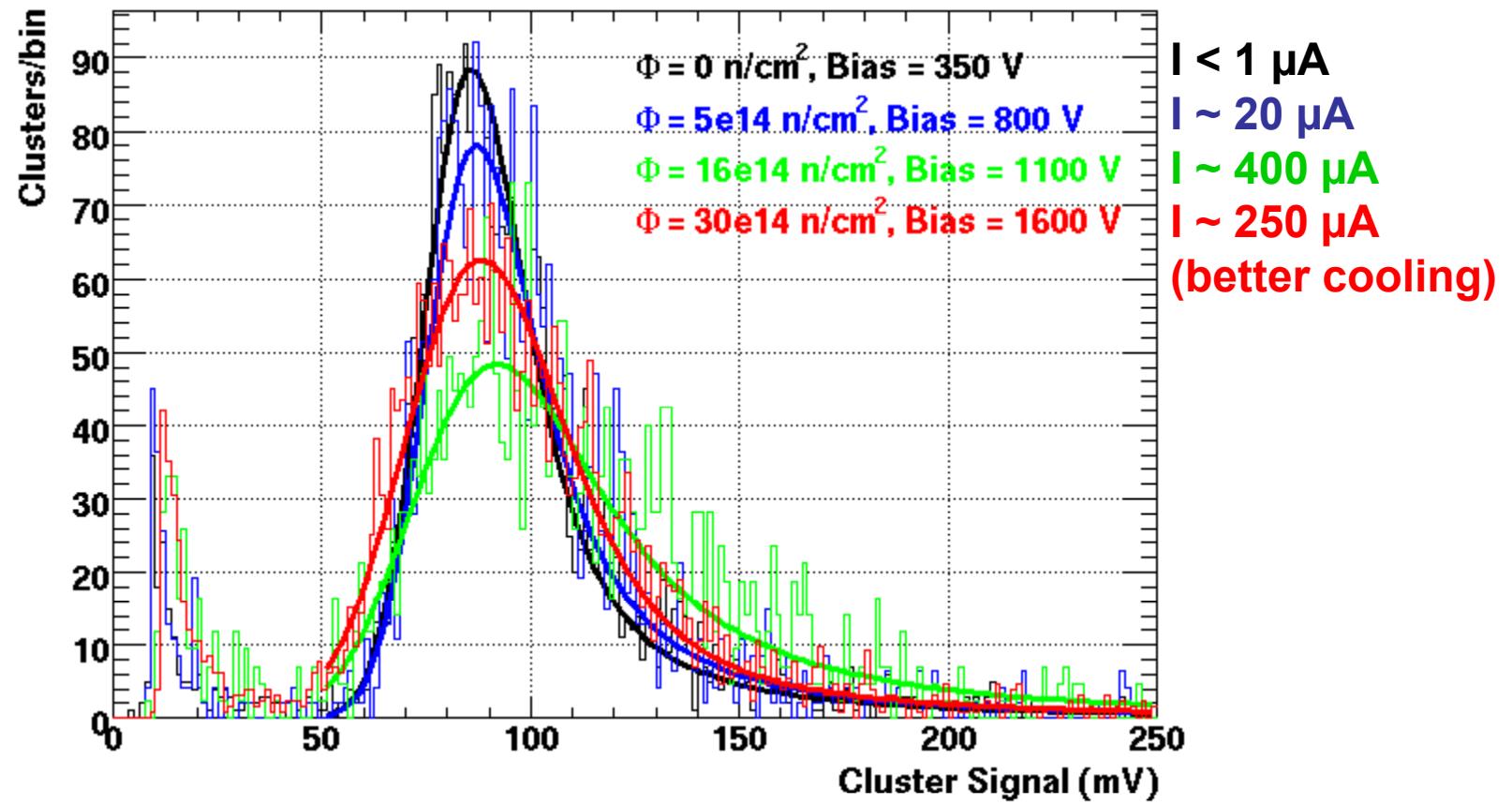
## Signal vs. Bias Voltage

- measurements taken at -20° C
- statistical error of points ~ 5%
- highest voltage limited by breakdown
- repeats of measurements are shown at two highest fluences (reproducibility test)



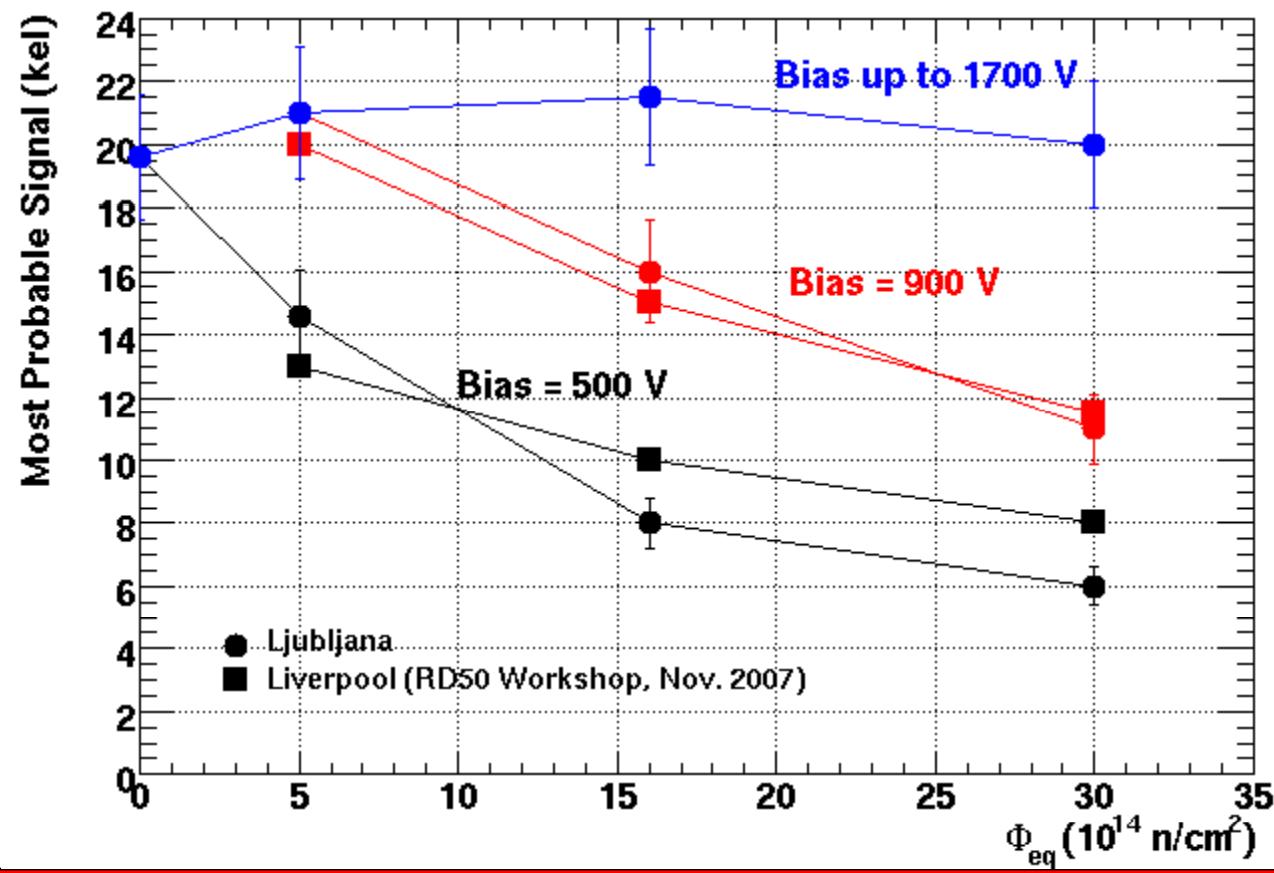
Comparison of spectra in which MP  $\sim$  20 kel measured after different fluences  
(normalized to the equal number of clusters in histogram)

- signals at high voltage after irradiation as high as before irradiation



## Signal vs. Fluence

- good agreement with Liverpool results
- with present cabling in ATLAS the highest voltage is 500 V
- it seems that higher bias voltage would help

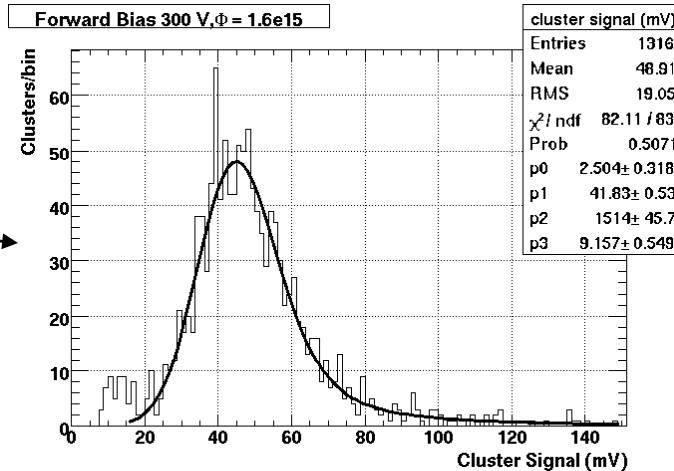


## Forward Bias

- after very high fluence detectors can be operated under forward bias

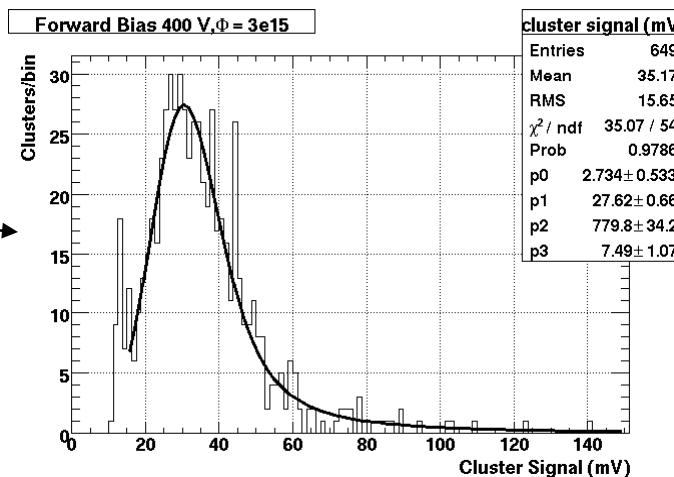
$\Phi = 1.6 \cdot 10^{15} \text{ n/cm}^2$ ,  $T \sim -40^\circ \text{ C}$   
 (a cup of liquid  $\text{N}_2$  put into the fridge)  
 Bias = +300 V,  $I = 200 \mu\text{A}$ ,  
MPV = 10 kel

Reverse bias  $\sim -600 \text{ V}$  needed  
 for same MPV, but much lower  
 current (less than 10  $\mu\text{A}$  at this T)



$\Phi = 3 \cdot 10^{15} \text{ n/cm}^2$ ,  $T \sim -24^\circ \text{ C}$ ,  
 Bias = +400 V,  $I = 600 \mu\text{A}$ ,  
MPV = 6.5 kel

Reverse bias  $\sim -600 \text{ V}$  needed  
 for same MPV, but much lower  
 current (35  $\mu\text{A}$  at this T)



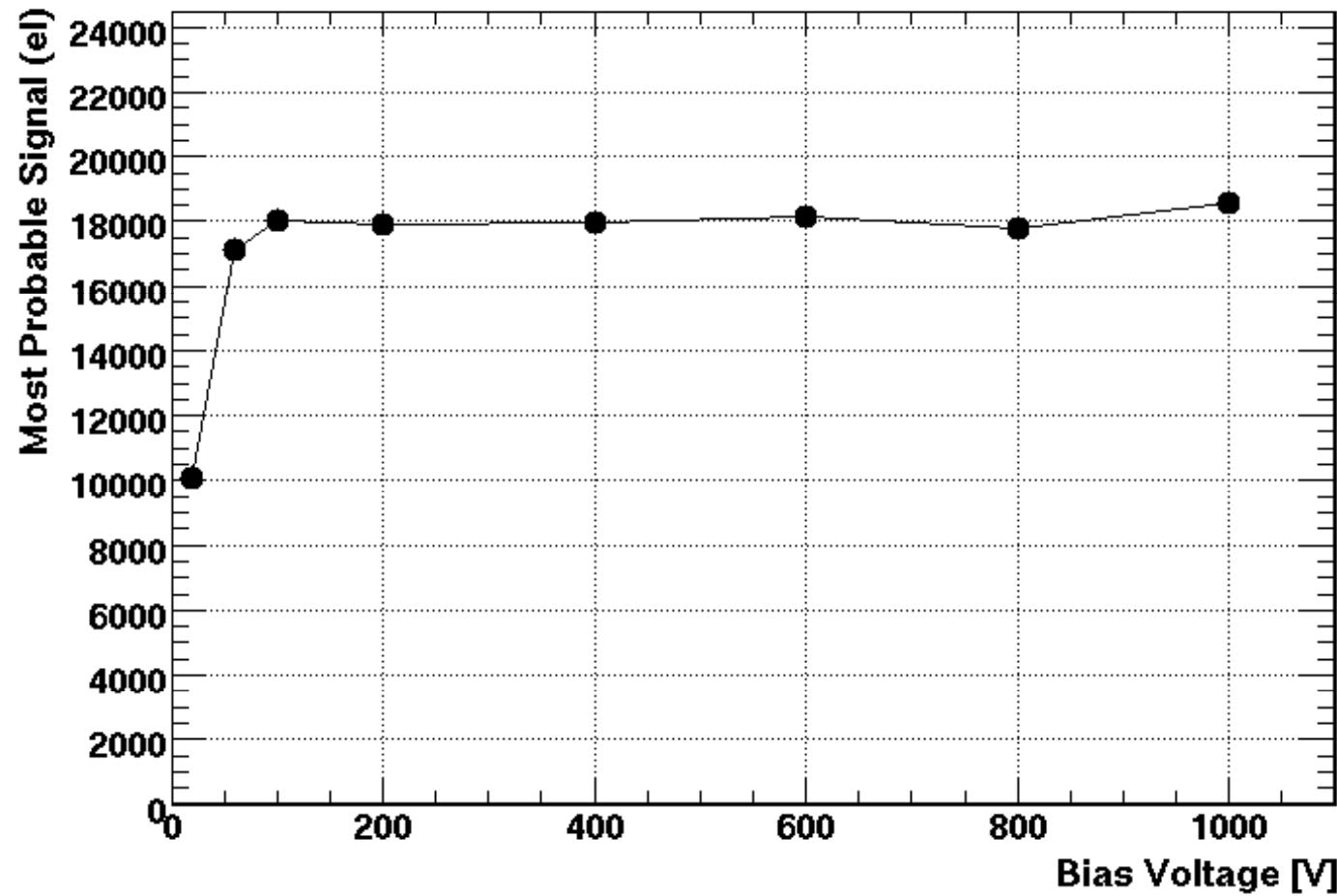
## Conclusions

- signals caused by fast electrons from  $^{90}\text{Sr}$  source in p-type microstrip detectors were measured with SCT128 chip
- measurements were made up to very high bias voltages (max.1700 V)
- CCE as high as before irradiation measured at sufficiently high voltage in detectors irradiated up to  $\Phi = 3 \cdot 10^{15} \text{ n/cm}^2$
- good agreement with measurements from Liverpool

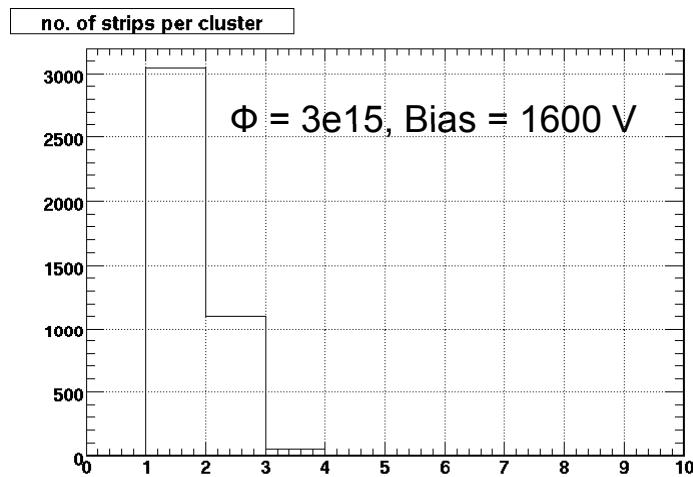
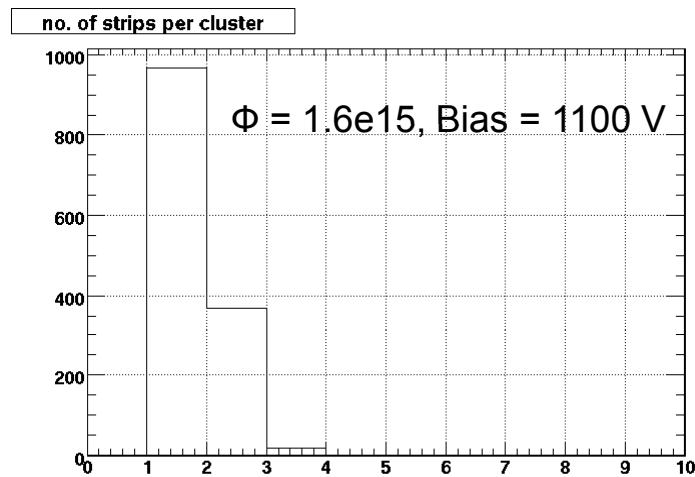
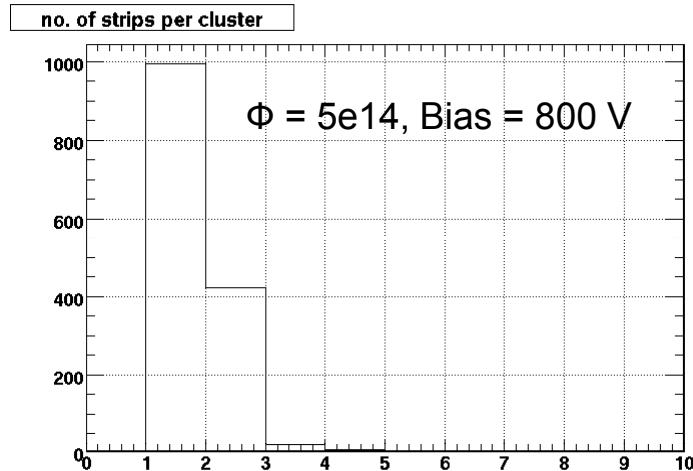
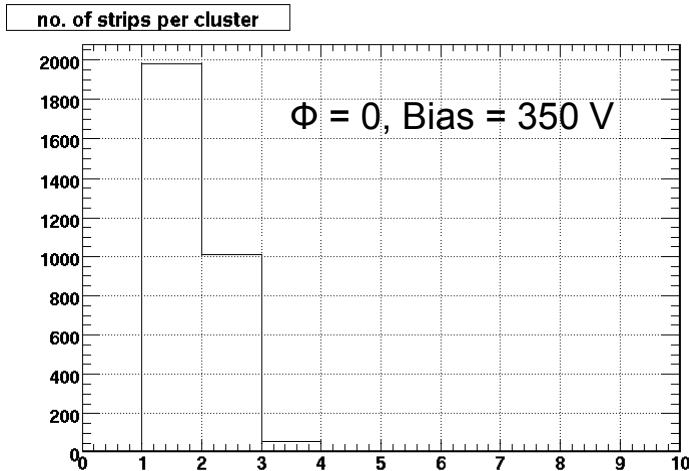


## Backup plots

Modul 0,  $\Phi_{\text{eq}} = 0 \text{ n/cm}^2$ , exposed to few Mrads of gammas

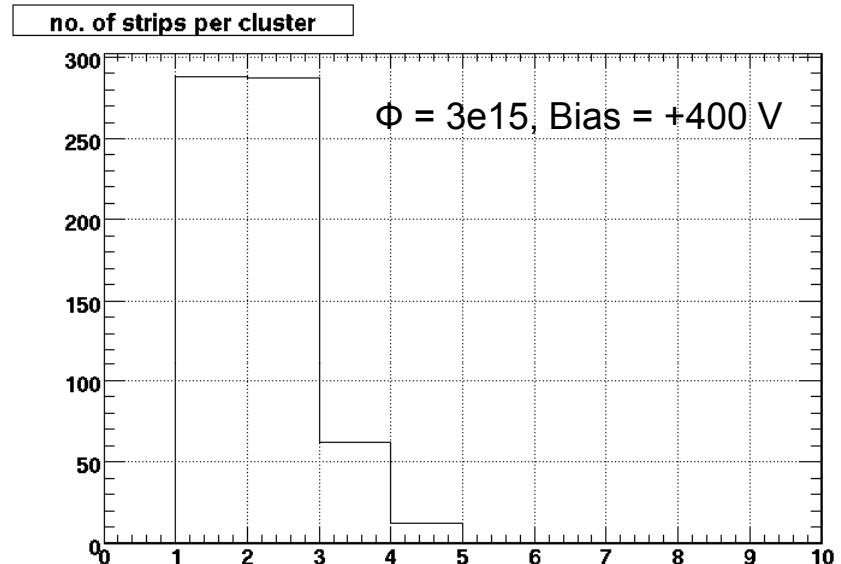
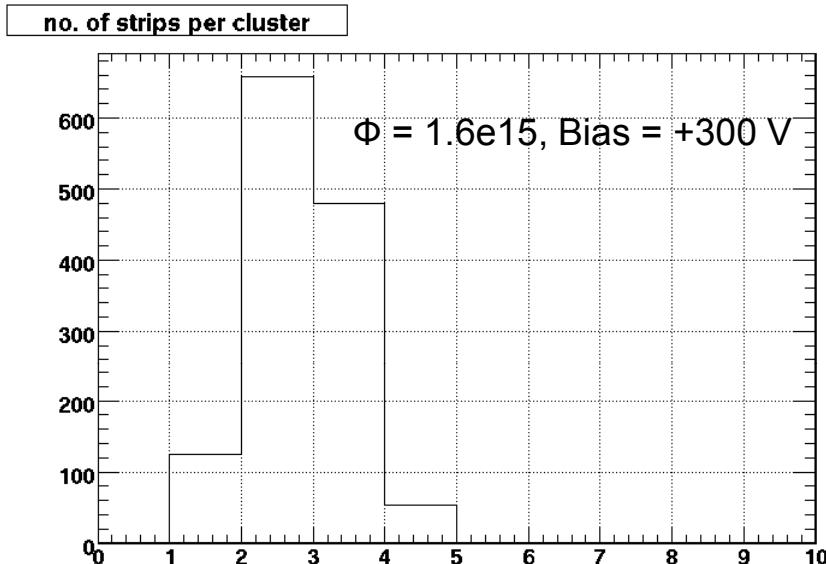


## Number of strips per cluster



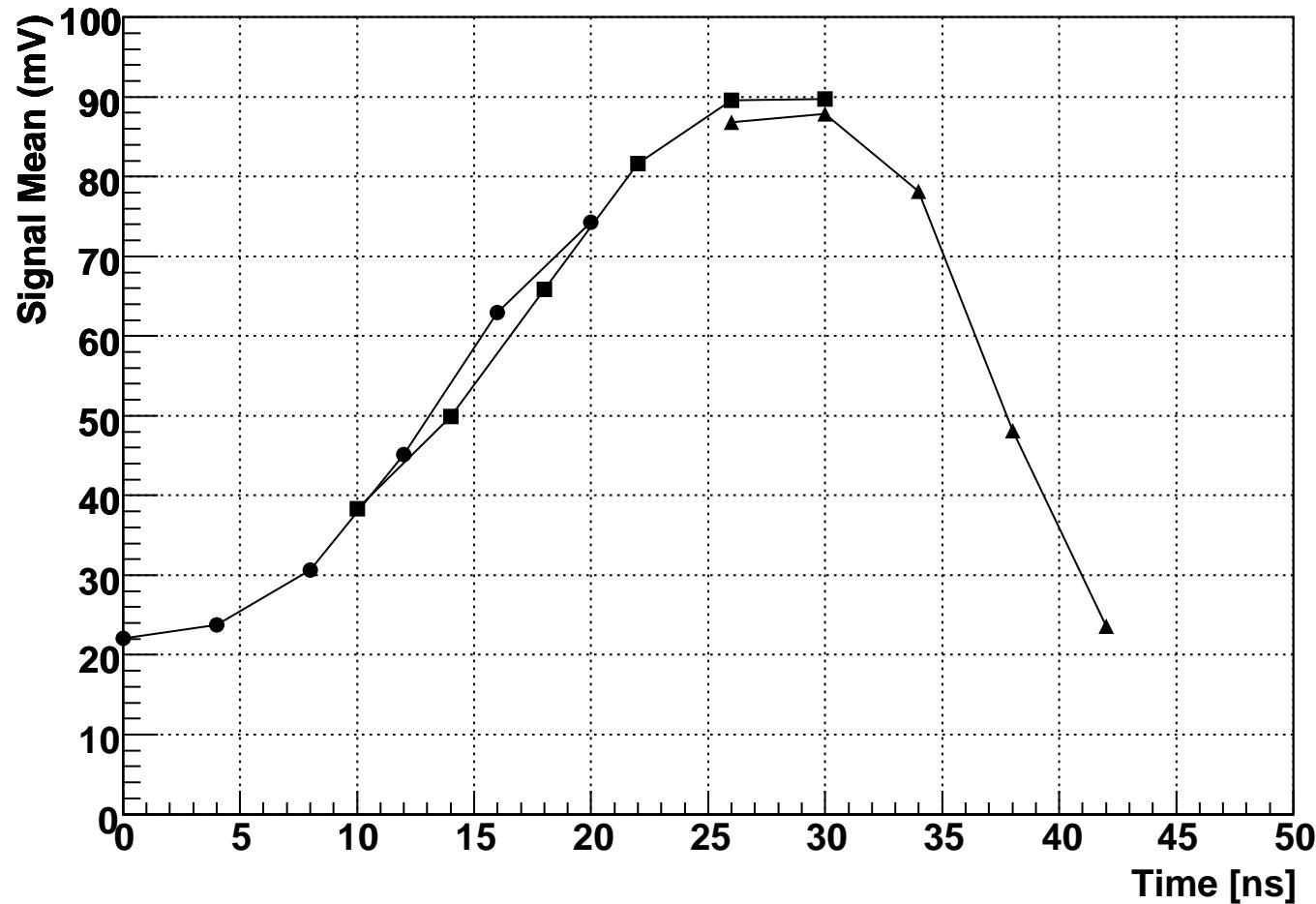
## Number of strips per cluster

- forward bias



## Pulse shape

- signal mean vs. trigger delay, before irradiation
- Bias = 200 V



## Signal to noise

- measurements for which MPV  $\sim 20000$  el

